

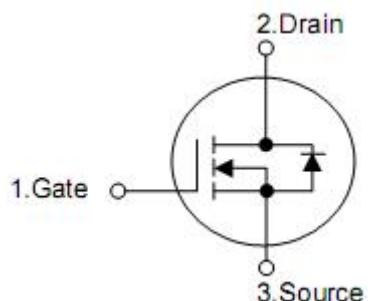
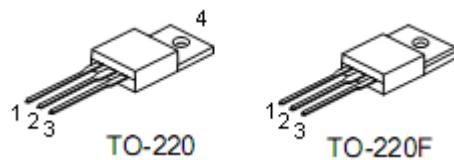
## 1. Description

The KIA12N60H N-Channel enhancement mode silicon gate power MOSFET is designed for high voltage, high speed power switching applications such as high efficiency switched mode power supplies, active power factor correction, electronic lamp ballasts based on half bridge topology.

## 2. Features

- $R_{DS(on)} = 0.53\Omega$  @  $V_{GS} = 10$  V
- Low gate charge ( typical 52nC)
- Fast switching capability
- avalanche energy specified
- Improved dv/dt capability

## 3. Pin configuration



Pin	Function
1	Gate
2	Drain
3	Source
4	Drain

#### 4. Absolute maximum ratings

( $T_C = 25^\circ\text{C}$ , unless otherwise specified)

Parameter	Symbol	Rating		Units
		TO-220	TO-220F	
Drain-source voltage	$V_{DSS}$	600		V
Drain-source voltage	$V_{GSS}$	$\pm 30$		V
Drain current continuous	$I_D$	12.0	12.0*	A
		7.4	7.4*	A
Drain current pulsed (note 1)	$I_{DP}$	48.0	48*	A
Avalanche energy	Repetitive (note 1)	23.1		mJ
	Single pulse (note 2)	865		mJ
Peak diode recovery dv/dt (note 3)	dv/dt	4.5		V/ns
Total power dissipation	$P_D$	231	54	W
		1.85	0.43	W/ $^\circ\text{C}$
Junction temperature	$T_J$	+150		$^\circ\text{C}$
Storage temperature	$T_{STG}$	-55~+150		$^\circ\text{C}$

\*Drain current limited by maximum junction temperature.

#### 5. Thermal characteristics

Parameter	Symbol	Rating		Unit
		TO-220	TO-220F	
Thermal resistance, Junction--ambient	$R_{thJA}$	62.5		$^\circ\text{C/W}$
Thermal resistance, case-to-sink typ.	$R_{thCS}$	0.5	-	$^\circ\text{C/W}$
Thermal resistance, Junction-case	$R_{thJC}$	0.54	2.33	$^\circ\text{C/W}$

## 6. Electrical characteristics

( $T_J=25^\circ\text{C}$ , unless otherwise notes)

Parameter	Symbol	Conditions	Min	Typ	Max	Unit
<b>Off characteristics</b>						
Drain-source breakdown voltage	$\text{BV}_{\text{DSS}}$	$V_{\text{GS}}=0\text{V}, I_{\text{D}}=250\mu\text{A}$	600	-	-	V
Zero gate voltage drain current	$I_{\text{DSS}}$	$V_{\text{DS}}=600\text{V}, V_{\text{GS}}=0\text{V}$	-	-	1	$\mu\text{A}$
		$V_{\text{DS}}=480\text{V}, T_c=125^\circ\text{C}$	-	-	10	$\mu\text{A}$
		$V_{\text{GS}}=30\text{V}, V_{\text{DS}}=0\text{V}$	-	-	100	nA
Gate-body leakage current	<b>Forward</b> <b>Reverse</b>	$V_{\text{GS}}=-30\text{V}, V_{\text{DS}}=0\text{V}$	-	-	-100	nA
Breakdown voltage temperature coefficient	$\Delta \text{BV}_{\text{DSS}}/\Delta T_J$	$I_{\text{D}}=250\mu\text{A}$	-	0.7	-	$\text{V}/^\circ\text{C}$
<b>On characteristics</b>						
Gate threshold voltage	$V_{\text{GS}(\text{th})}$	$V_{\text{DS}}=V_{\text{GS}}, I_{\text{D}}=250\mu\text{A}$	2.0	-	4.0	V
Static drain-source on-resistance	$R_{\text{DS}(\text{on})}$	$V_{\text{GS}}=10\text{V}, I_{\text{D}}=6.0\text{A}$	-	0.53	0.65	$\Omega$
<b>Dynamic characteristics</b>						
Input capacitance	$C_{\text{iss}}$	$V_{\text{DS}}=25\text{V}, V_{\text{GS}}=0\text{V}, f=1\text{MHz}$	-	1850	-	pF
Output capacitance	$C_{\text{oss}}$		-	180	-	pF
Reverse transfer capacitance	$C_{\text{rss}}$		-	20	-	pF
<b>Switching characteristics</b>						
Turn-on delay time	$t_{\text{d}(\text{on})}$	$V_{\text{DD}}=300\text{V}, I_{\text{D}}=12.0\text{A}, R_{\text{G}}=25\Omega$ (note 4,5)	-	30	-	ns
Rise time	$t_r$		-	90	-	ns
Turn-off delay time	$t_{\text{d}(\text{off})}$		-	140	-	ns
fall time	$t_f$		-	90	-	ns
Total gate charge	$Q_g$	$V_{\text{DS}}=480\text{V}, I_{\text{D}}=12.0\text{A}$ $V_{\text{GS}}=10\text{V}$ , (note 4,5)	-	52	-	nC
Gate-source charge	$Q_{\text{gs}}$		-	8.5	-	nC
Gate-drain charge	$Q_{\text{gd}}$		-	20	-	nC
<b>Drain-source diode characteristics</b>						
Drain-source diode forward voltage	$V_{\text{SD}}$	$V_{\text{GS}}=0\text{V}, I_{\text{SD}}=12.0\text{A}$	-	-	1.4	V
Continuous drain-source current	$I_{\text{SD}}$		-	-	12.0	A
Pulsed drain-source current	$I_{\text{SM}}$		-	-	48.0	A
Reverse recovery time	$t_{\text{rr}}$	$I_{\text{SD}}=12.0\text{A}$ $dI_{\text{SD}}/dt=100\text{A}/\mu\text{s}$ (note 4)	-	430	-	ns
Reverse recovery charge	$Q_{\text{rr}}$		-	5.0	-	$\mu\text{C}$

Note: 1.repetitive rating : pulse width limited by maximum junction temperature

2. $L=11\text{mH}, I_{\text{AS}}=12.0\text{A}, V_{\text{DD}}=50\text{V}, R_{\text{G}}=25\Omega$ ,staring  $T_J=25^\circ\text{C}$

3. $I_{\text{SD}}\leq 12.0\text{A}, dI/dt\leq 200\text{A}/\mu\text{s}, V_{\text{DD}}\leq \text{BV}_{\text{DSS}}$ ,staring  $T_J=25^\circ\text{C}$

4.Pulse test:pulse width $\leq 300\mu\text{s}$ ,duty cycle $\leq 2\%$

5.Essentially independent of operating temperature

## 7. Test circuits and waveforms

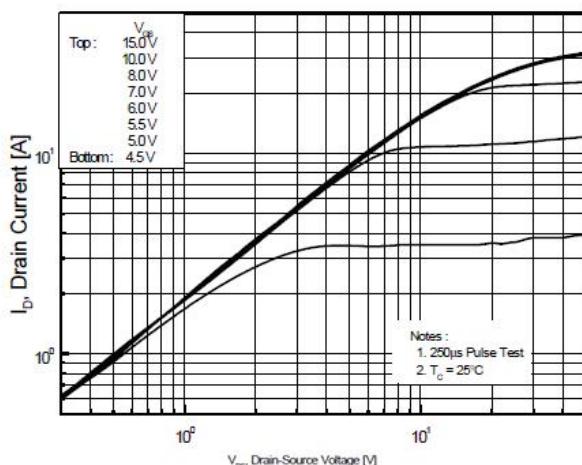


Figure 1. On-Region Characteristics

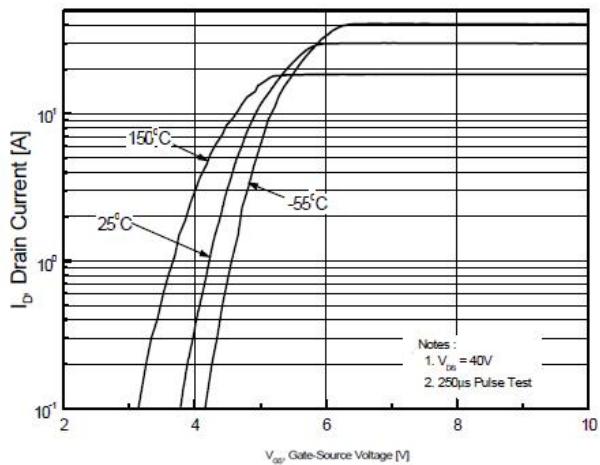


Figure 2. Transfer Characteristics

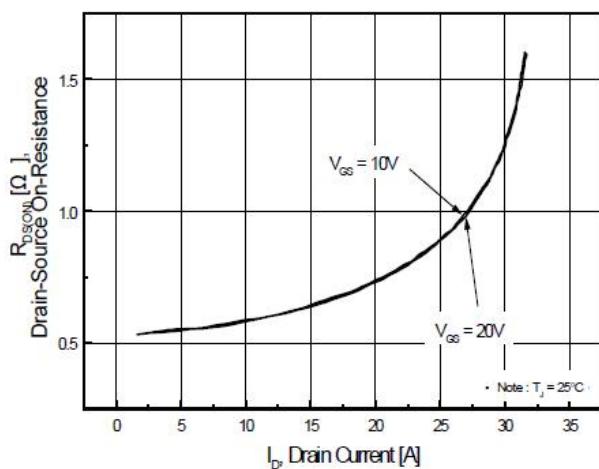


Figure 3. On-Resistance Variation vs  
Drain Current and Gate Voltage

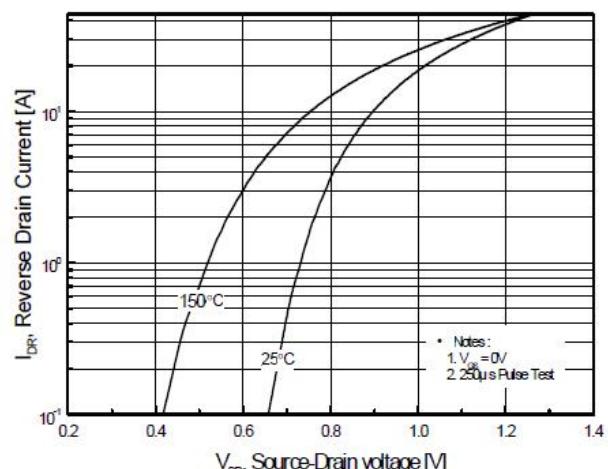


Figure 4. Body Diode Forward Voltage Variation  
with Source Current and Temperature

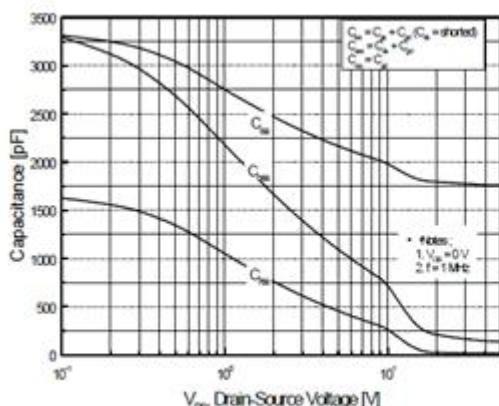


Figure 5. Capacitance Characteristics

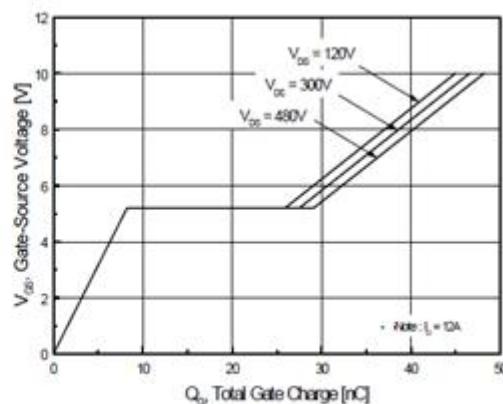
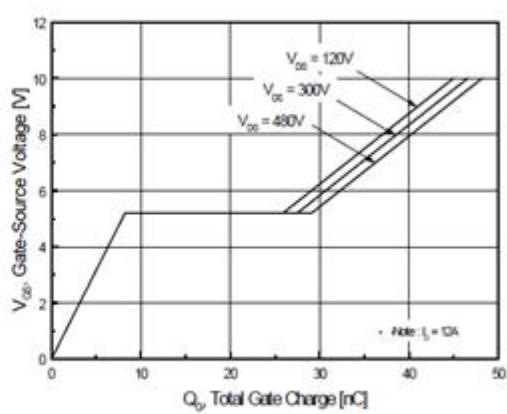
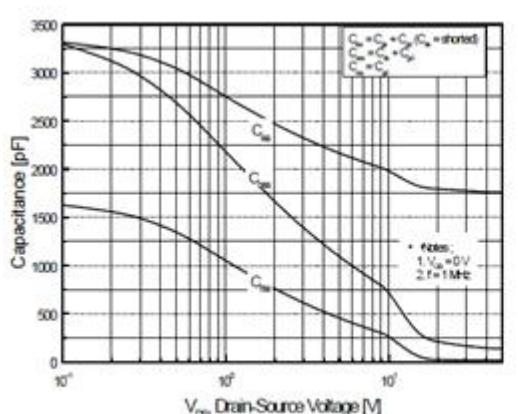
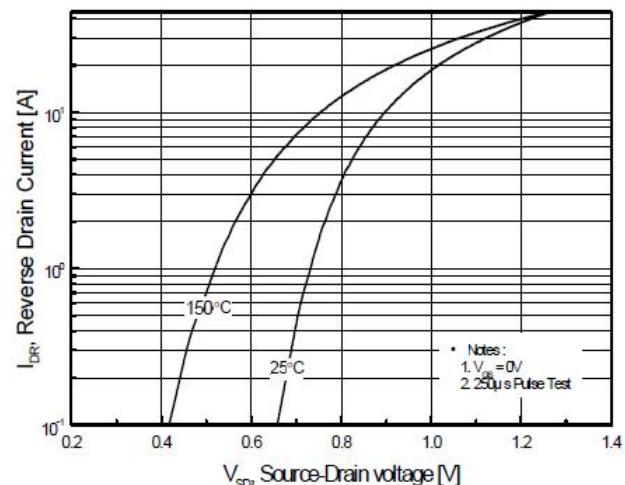
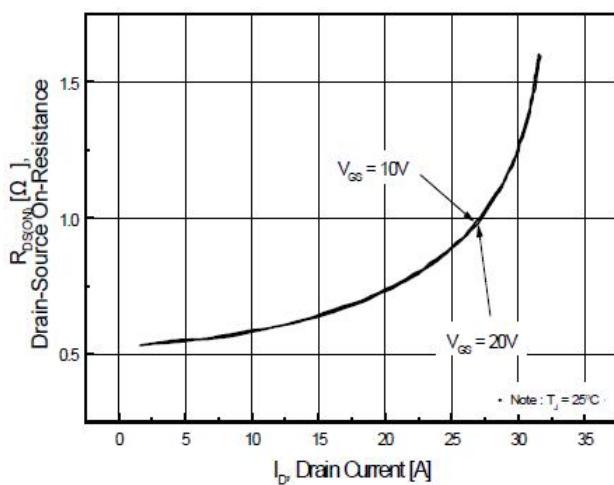
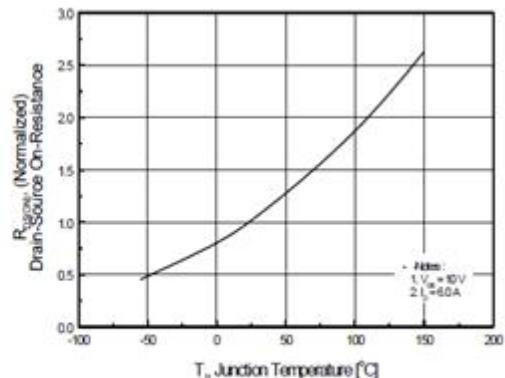
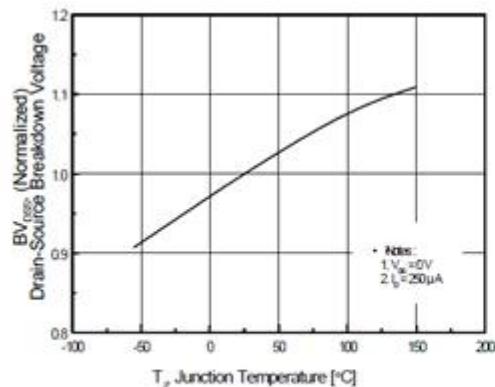


Figure 6. Gate Charge Characteristics



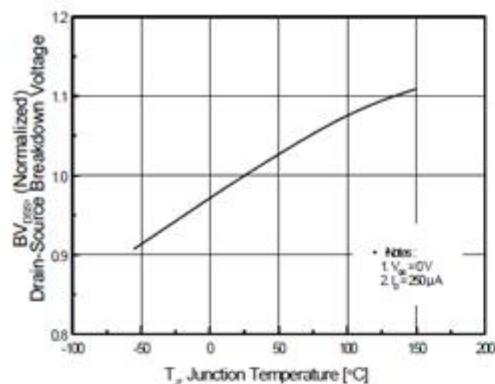


Figure 7. Breakdown Voltage Variation vs Temperature

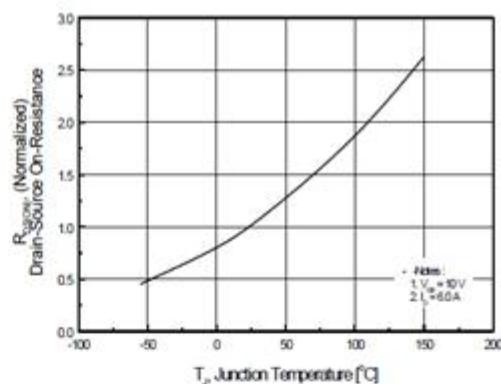


Figure 8. On-Resistance Variation vs Temperature

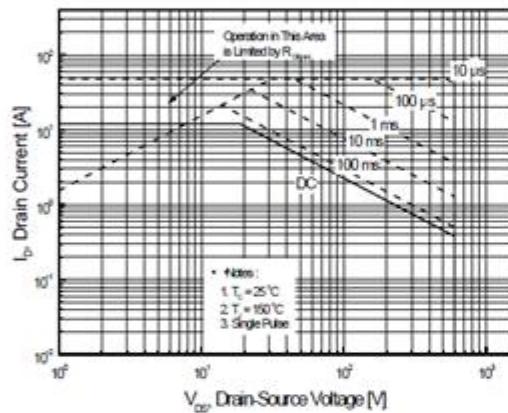


Figure 9-1. Maximum Safe Operating Area for TO220

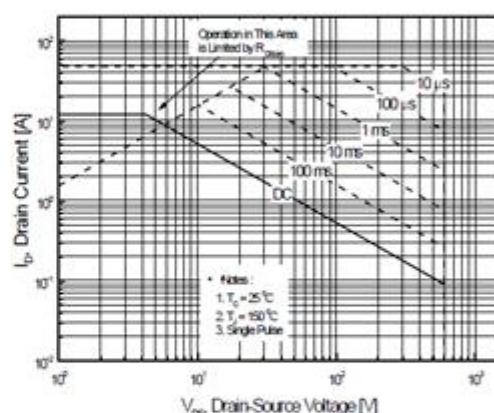


Figure 9-2. Maximum Safe Operating Area for TO220F

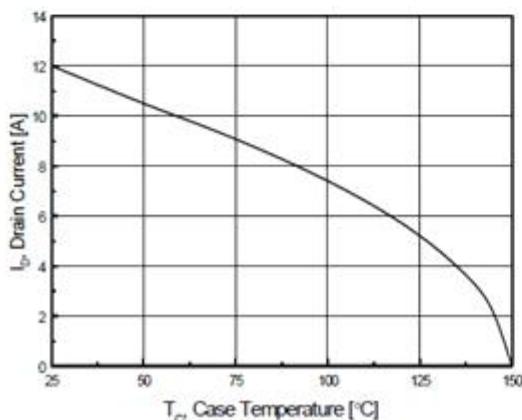


Figure 10. Maximum Drain Current vs Case Temperature

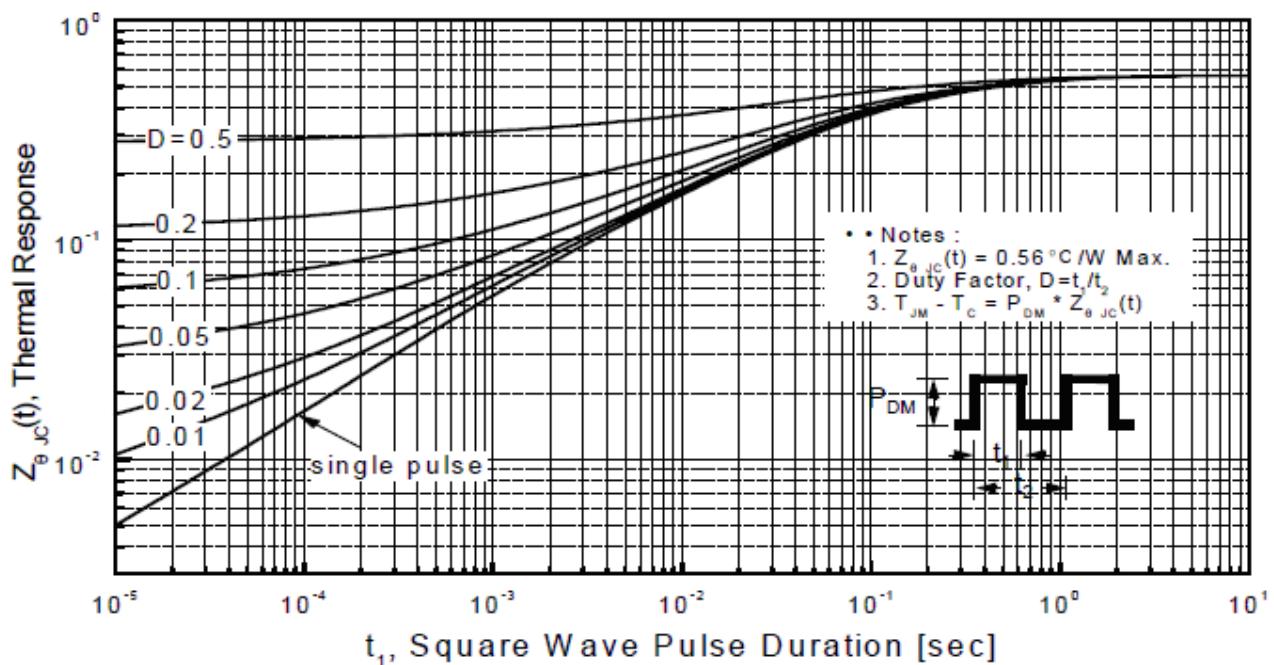


Figure 11-1. Transient Thermal Response Curve for TO220

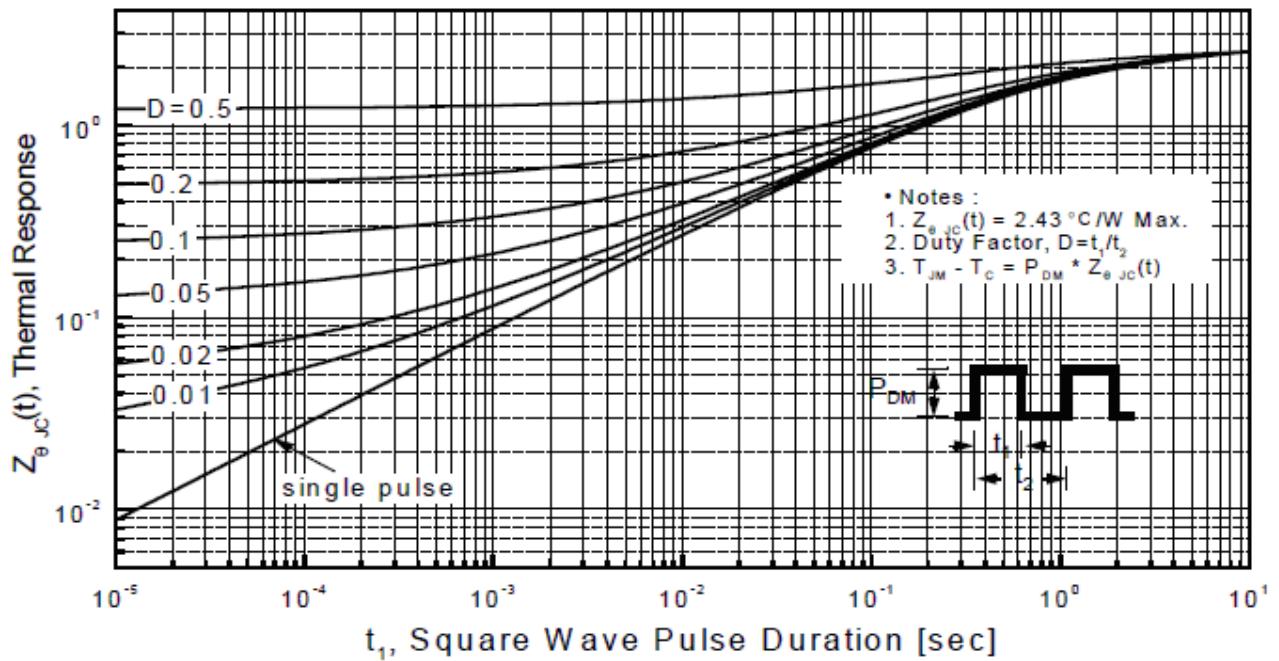


Figure 11-2. Transient Thermal Response Curve for TO220F